

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

Applicant(s) : Heon Jin CHOI, Jae Chul PYUN  
Serial No. : Not Yet Assigned  
For : NANOWIRE ASSISTED LASER  
DESORPTION/IONIZATION MASS SPECTROMETRIC  
ANALYSIS  
Filed :  
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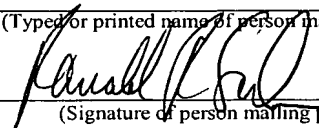
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**TRANSMITTAL OF INFORMATION DISCLOSURE STATEMENT**  
**UNDER 37 CFR 1.97(B)**

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Dear Sir:

The Information Disclosure Statement submitted herewith is being filed within three months of the filing of a national application; within three months of the date of entry of the national stage as set forth in 37 CFR 1.491 in an international application; or before the mailing date of a first Office Action on the merits, whichever event occurs last. No fee is required.

The filing of this Information Disclosure Statement is not an admission that the documents identified herein constitute prior art to the present application.

The Commissioner is authorized to charge any additional fee that may be required to Deposit Account No. 50-0320.

Respectfully submitted,  
FROMMER LAWRENCE & HAUG LLP

By:



Ronald R. Santucci

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Based on Form PTO-1449 (3/90)  LIST OF REFERENCES CITED BY APPLICANT (Use several sheets if necessary)	ATTY. DOCKET NO. <b>930086-2038</b>	SERIAL NO. <b>TO BE ASSIGNED</b>
	APPLICANT <b>Heon Jin CHOI, et al.</b>	
	FILING DATE <b>TO BE ASSIGNED</b>	GROUP <b>TO BE ASSIGNED</b>

## U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	AA	2003/0052006 A1	03/20/03	Noca et al.	204	450	
	AB	6,288,390 B1	09/11/01	Siuzdak et al.	250	288	
	AC						
	AD						
	AE						
	AF						

## FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
	AG	08-315633	11/29/96	Japan			Abst.	
	AH	10-2001-0081780	06/25/03	Korea			Abst.	
	AI							
	AJ							
	AK							

## OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)

	AL	Min-Jung Kang, et al., "Application of Automated Matrix-Assisted Laser Desorption/Ionization Time-of-Flight Mass Spectrometry For The Measurement Of Enzyme Activities", Rapid Commun. Mass Spectrom. 2001; 15: pp. 1327-1333.
	AM	Jing Wei, et al., "Desorption-Ionization Mass Spectrometry on Porous Silicon", (1999) Nature, Vol. 399, 243-246.
	AN	Warren G. Lewis, et al., "Desorption/Ionization on Silicon (DIOS) Mass Spectrometry: Background and Applications, International Journal of Mass Spectrometry, 226 (2003) pp. 107-116
	AO	Justin C. Johnson, et al., "Single Gallium Nitride Nanowire Lasers, Nature Materials, Vol. 1, October 2002) pp. 106-110.
	AP	Vladimir E. Frankevich, "Role of Electrons in Laser Desorption/Ionization Mass Spectrometry", Analytical Chemistry, Vol. 75 No. 22, November 15, 2003, pp. 6063-6067.
	AQ	G/ Siuzdak, I. Ion Sources and Sample Introduction, In: Mass Spectroscopy for Biotechnology, Academic Press, 1996, p. 13.
	AR	J.M. Bermond, et al. Sur. Sci. 42 (1974) p. 306
	AS	
	AT	

EXAMINER

DATE CONSIDERED

\* EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.